

Docket No.: 061282-0048



PATENT

ZFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	Customer Number: 20277
Shinya TOKUNAGA, et al.	:	Confirmation Number: 4744
Application No.: 10/722,346	:	Group Art Unit: 2825
Filed: November 26, 2003	:	Examiner: SIEK, VUTHE

For: MASK PATTERN INSPECTING METHOD, INSPECTION APPARATUS, INSPECTING DATA USED THEREIN AND INSPECTING DATA GENERATING METHOD

RESPONSE UNDER 37 C.F.R. § 1.111

Mail Stop Amendment
Honorable Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to Office Action dated February 6, 2006, having a shortened statutory period for response set to expire on Saturday, May 6, 2006, Applicants respectfully request reconsideration of the pending rejection for the following reasons.